

Arnost Neugroschel

List of Publications by Year in descending order

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2258059

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2550090

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docs citations

3
times ranked

75
citing authors

#	ARTICLE	IF	CITATIONS
1	Investigation of negative bias temperature instability dependence on fin width of silicon-on-insulator-fin-based field effect transistors. Journal of Applied Physics, 2015, 117, .	2.5	7
2	Gated Diode Investigation of Bias Temperature Instability in High- κ FinFETs. IEEE Electron Device Letters, 2010, 31, 653-655.	3.9	13
3	Effect of the Interfacial SiO_2 Layer in High- κ HfO_2 Gate Stacks on NBTI. IEEE Transactions on Device and Materials Reliability, 2008, 8, 47-61.	2.0	32